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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of:

Hae-seok PARK et al.

Art Unit: 2862

Serial No. 10/763,394

Examiner: David M. Schindler

Filed: January 26, 2004

Confirmation No. 4583

For: FLUXGATE SENSOR INTEGRATED IN A
SEMICONDUCTOR SUBSTRATE AND
METHOD FOR MANUFACTURING THE
SAME

Attorney Docket No. 277/044

AMENDMENT UNDER 37 C.F.R. § 1.111

Mail Stop Amendment
Commissioner for Patents
United States Patent and Trademark Office
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INTRODUCTORY COMMENTS

In response to the Office action dated December 16, 2005 and the March 15, 2006 personal interview, the following amendments and remarks are respectfully submitted in connection with the above-identified application:

Amendments to the Claims are reflected in a listing of claims, which begins on page 2 of this paper.

Remarks begin on page 11 of this paper.